Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/780,938	HAYASHI, HIROKAZU	
Examiner	Art Unit	
Paul Diph	2825	

SEARCHED					
Class	Subclass	Date	Examiner		
716	4-5, 11, 18	8/26/2005	PD		
438	17-18	8/26/2005	PD		
324	658	8/26/2005	PD		
324	763,765	8/26/2005	PD		
257	48	8/26/2005	·PD		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
search	above	8/26/2005	PD	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST. IEEE	8/26/2005	PD		
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